

<b>Notice of References Cited</b>	Application/Control No. 10/631,042	Applicant(s)/Patent Under Reexamination SHAH ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,836,773	12-2004	Tamayo et al.	707/6
*	B	US-6,694,307	02-2004	Julien, Benoit	707/3
*	C	US-6,671,818	12-2003	Mikurak, Michael G.	714/4
*	D	US-6,253,238	06-2001	Lauder et al.	709/217
*	E	US-6,101,537	08-2000	Edelstein et al.	709/219
*	F	US-2004/0260781	12-2004	Shostack et al.	709/207
*	G	US-2004/0249811	12-2004	Shostack et al.	707/005
*	H	US-2004/0167794	08-2004	Shostack et al.	705/001
*	I	US-2004/0143526	07-2004	Monasterio et al.	705/035
*	J	US-6,607,267	08-2003	Testardi et al.	347/100
*	K	US-6,119,933	09-2000	Wong et al.	235/380
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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